

# Letters

## Data-Driven Adaptive Open-Circuit Fault Localization Method With Reduced Sensors for Magnetic-Network Energy Router

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**Abstract**—Fault localization is a critical challenge for magnetic-network energy router (MNER) consisting of numerous switches. This letter proposes a data-driven adaptive open-circuit fault localization method with reduced sensors for MNER. Through the extraction of adaptive data ensembles from interarm voltage sampling channels, numerous time-sliding ensemble anomaly encoders (EAEs) are constructed to isolate the abnormal channels. Next, by means of buffering and decoding the EAE's output, the faulty switch can be effectively localized. The proposed method not only reduces fault feature dimensionality, thereby minimizing the requirement for extra hardware, but also eliminates the reliance on mathematical model and threshold setting. A 2-kW MNER experimental platform is constructed to verify the effectiveness of the proposed method.

**Index Terms**—Data-driven, fault localization, magnetic network energy router (MNER), open-circuit fault (OCF).

### I. INTRODUCTION

MAGNETIC-NETWORK energy router (MNER) has emerged as a focus of interest in the family of isolated multiport dc–dc converters, due to its unique advantages of reliable electrical isolation and highly integrated design [1], [2], [3], [4]. Reliability is crucial for MNER, which consists of numerous power electronic switches. Each switch can trigger a potential open-circuit fault (OCF), generating the overcurrent and transformer saturation, causing secondary damage. Therefore, an efficient OCF localization method is vital for the safe operation of MNER [5].

The methods of OCF localization in isolated multiport dc–dc converters can be broadly classified into two categories: model-based method and data-based methods. The model-based

methods rely on the math models to describe the normal and faulty behaviors, by applying Kalman filter and other state observers for fault localization [6], [7]. The model-based methods require constructing precise model of MNER. However, the characteristics of nonlinear and magnetic-coupling within MNER not only complicates the modelling, but also demands computational resources and introduce delays in the localization process. In addition, the model-based methods require manual threshold setting, which depends on trial-and-error adjustments, leading to degrading localization performance under the operation condition variations.

Data-based method is another category, which avoids constructing complex mathematical model in contrast with model-based ones. In [8], the ac-side voltage of transformer is applied in fault detection, but it fails to localize faults in specific switches. In [9], auxiliary windings and current sensors are introduced to detect primary-side voltage, which increases hardware cost. In [10], [11], and [12], the arm voltage and inductor current are applied as diagnosis criteria, but it requires individual voltage sensors and current sensors installed on every arm, imposing hardware overhead. Several artificial intelligence methods, such as finite state machines [13] and neural networks [14], have been adopted for fault localization for dual-active bridge converter. However, these methods fail to effectively address multiswitch faults, and their complex computational requirements affect the efficiency of fault localization. Moreover, the existing data-based methods still require manual threshold setting, hindering their feasibility.

To address the above issues of complicated modeling, threshold setting, and hardware overhead associated with existing methods, this letter proposes a data-driven adaptive fault localization method for MNER. First, the data windows of interarm voltages (IVs) are employed as input channels for ensemble anomaly encoders (EAEs). Subsequently, the data features such as the baseline mean and standard deviation of each channel are adaptively established. After that, these features are fed into the EAEs and determine the EAE's outputs (EAEs), by calculating the mean depth (MD) of each channel. Finally, the fault switch is localized through buffering and decoding the EAEs.

The primary contributions of the proposed method include the following.

- 1) It decreases hardware costs through the reduction of voltage sensors and eliminating auxiliary windings compared

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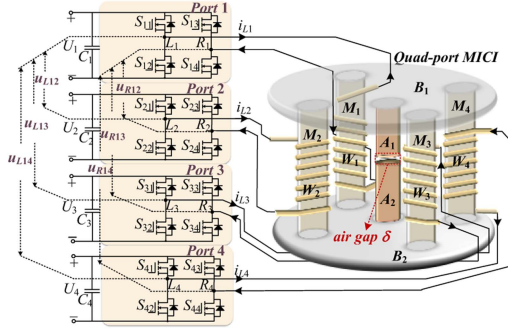


Fig. 1. Topology structure of quad-port MNER.

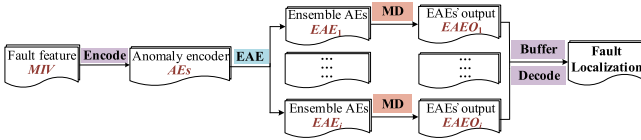


Fig. 2. Proposed data-driven adaptive fault localization method for MNER.

with [6], [7], [8], [9], [10] and [12], due to the innovative utilization of the relationship among IVs.

- 2) It enhances the speed and accuracy of fault localization, by directly employing lightweight anomaly encoder (AE) and leveraging the sparsity-based fault identification, instead of setting thresholds and conducting complicated models in contrast with [6], [7], [8], [9], [10], [11] and [12].
- 3) It innovatively enables concurrent multiswitch fault localization through a scalable composite decoder in contrast with [13] and [14].

## II. QUAD-PORT MAGNETIC-NETWORK ENERGY ROUTER

Fig. 1 shows the topology structure of a quad-port MNER where four full-bridges are linked by the magnetic integrated coupled inductor (MICI), which reduces the size and elevates power density of MNER. The MICI is composed of four windings  $W_1 \sim W_4$  wound on corresponding magnetic columns  $M_1 \sim M_4$ . The columns  $M_1 \sim M_4$  feature an annular region  $A_1 \sim A_2$  with an interposed air gap  $\delta$ , and position between two cylindrical disks  $B_1 \sim B_2$ . The windings  $W_1 \sim W_4$  are respectively connected to the ac side of ports 1–4, while  $i_{L1} \sim i_{L4}$  denote the corresponding currents flowing through the windings. Each bridge in MNER contains four switches, and capacitors  $C_1 \sim C_4$  are parallelly connected to dc voltages  $U_1 \sim U_4$ . With port 1 serving as the reference,  $u_{L12} \sim u_{L14}$ ,  $u_{R12} \sim u_{R14}$  respectively denote the IVs of ports 2–4 in relation to  $u_{L1}$ ,  $u_{R1}$ .

## III. PROPOSED DATA-DRIVEN FAULT LOCALIZATION METHOD

Normally, complicated modeling and threshold setting are required for fault localization, degrading its speed and accuracy. To address the issue, the data-driven adaptive fault localization method is proposed for MNER, as shown in Fig. 2. First, the fault feature of IVs is extracted and averaged into mean interarm voltages (MIVs) using sliding-time window (STW). Subsequently, the AEs are constructed by establishing adaptive

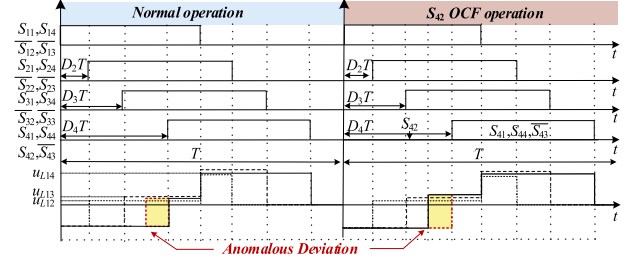


Fig. 3. Waveforms of drive signals, mid-point voltages and IVs.

baseline mean and standard deviation of MIVs. Furthermore, the EAE for MNER is constructed based on neighboring AEs. Afterwards, determined by the MD within AEs, the EAE0 is being continuously buffered and decoded to achieve final localization.

### A. MIV-Based Fault Feature Selection

Fig. 3 shows the waveforms of drive signals and IVs under single-phase shift (SPS) modulated MNER, during both normal operation and OCF operation.  $T$  stands for the switching period. Under normal operation, each  $u_{L1i}$  ( $i = 2, 3, 4$ ) in the SPS-modulated MNER successively lags behind by phase-shift angles  $D_2 \sim D_4$ . However, once OCF occurs to  $S_{42}$ , its corresponding drive signal is simultaneously disabled. As a result, the  $u_{L14}$  associated with  $S_{42}$  is forced into an unbalanced state, generating a sustained anomalous deviation. Notably, the deviation exhibits complementary half-cycle identity to the right-arm waveforms  $u_{R1i}$  ( $i = 2, 3, 4$ ).

Within each full-bridge of MNER, when  $i_{L_i}$  ( $i = 1, 2, 3, 4$ ) flows through the upper bridge arm, the corresponding arm voltage equals to the dc voltage of its associated port, and becomes zero when  $i_{L_i}$  passes through the lower arm. Under normal operating conditions, the switches in both upper and lower bridge arms maintain symmetrical conduction time of half a cycle each. As shown in Fig. 3, each MIV under normal operation can be obtained as

$$\begin{aligned}
 U_{L1i-N} = U_{R1i-N} &= \frac{\int_0^{D_i T} u_{L1i}(t) dt}{T} + \frac{\int_{D_i T}^{T/2-D_i T} u_{L1i}(t) dt}{T} \\
 &+ \frac{\int_{T/2-D_i T}^{T/2} u_{L1i}(t) dt}{T} \\
 &= -D_i U_1 + \left(\frac{1}{2} - D_i\right)(U_i - U_1) + D_i U_i = \frac{U_i - U_1}{2}
 \end{aligned} \quad (1)$$

where  $U_{L1i-N}$  and  $U_{R1i-N}$  stands for the MIV of left and right arm respectively under normal operation.

Conversely, after an OCF, MIV exhibits abnormal deviation, as given in Table I, due to the nonidentical conduction time between upper and lower arms. Because the deviation emerges only under OCF and not presents during normal operation, the MIVs could be selected as fault feature to be analyzed in EAE to achieve fault localization.

TABLE I  
MEAN VALUE OF INTERARM VOLTAGE UNDER FAULTS

Fault position	Faulty switch	Fault feature	Range
Upper arm	$S_{11}$	$U_{L1i}$	$< U_{L1iN}$
	$S_{13}$	$U_{R1i}$	$< U_{R1iN}$
Lower arm	$S_{12}$	$U_{L1i}$	$> U_{L1iN}$
	$S_{14}$	$U_{R1i}$	$> U_{R1iN}$

TABLE II  
EAE FOR MNER UNDER FAULT

Switch state	Channel depth	Channel MD
Normal	↑	↑
OCF	↓	↓

nodes would have a higher probability to store an anomalous channel, which exhibits smaller level in the EAE in contrast with normal channels.

#### D. EAE's Output for MNER

The EAEO is defined as the set of index and deviation type of the channels corresponding to the nodes exhibiting smaller MD, as the abnormal nodes in each EAE exhibit a high probability to contain the smaller MD. In each EAE, the  $MD(\lambda)$  of channel  $\lambda$  in a window length  $W$  is calculated as

$$MD(\lambda) = \frac{1}{W} \sum_{j=1}^W D(\lambda, j). \quad (3)$$

Following the EAE establishment for MNER, in order to classify the fault candidates in each EAE, the adaptive reference statistics: mean value  $\mu$  and standard deviation  $\sigma$  for channel  $\lambda$  at the  $k$ th sampling periods [15], are computed as

$$\begin{cases} \mu_{\lambda}(k) = \frac{1}{W} \sum_{a=k-W+1}^{a=k} I_i(a) \\ \sigma_{\lambda}(k) = \min \left\{ \sqrt{\frac{1}{W} \sum_{a=k-W+1}^{a=k} (I_i(a) - \mu_i)^2}, 0.02 \mu_i \right\} \end{cases} \quad (4)$$

The set of fault candidate channels is identified using channel-wise confidence scores  $C_{\lambda}(k)$  [15], determined as

$$\begin{cases} C_{\lambda}(k) = \frac{|I_{\lambda}(k) - \mu_{\lambda}|}{\sigma_i} \\ \Lambda(k) = \left\{ \lambda \mid C_{\lambda}(k) > \frac{2}{W} \sum_{j=\lambda-W+1}^{\lambda} \left[ \frac{1}{6} \sum_{j=1}^6 C_j(\lambda) \right] \right\} \end{cases} \quad (5)$$

where  $\Lambda(k)$  is the set of fault candidates at  $k$ th sampling periods.

Channels identified by (4) and (5) as fault candidates exhibit smaller values of  $MD$  in the EAE, in contrast with those under normal operation, as given in Table II.

Moreover, according to Table I, the deviation direction could be classified into two types as

$$\text{dir}_{\lambda} = \begin{cases} 1 & C_i(k) < 0, \text{ upper switch fault} \\ 2 & C_i(k) > 0, \text{ lower switch fault} \end{cases} \quad (6)$$

where  $\text{dir}_{\lambda}$  links the deviation direction type with switch position.

Consequently, a  $\lambda$ th channel fault induces the  $MD(\lambda)$  exhibiting a high probability to be smallest. Finally, the set of indexes  $\lambda$  and deviation types  $\text{dir}_{\lambda}$  corresponding to the fault candidate channels in EAE constitutes the EAEO, expressed as

$$\text{EAEO}(k) = \{(\lambda, \text{dir}_{\lambda}) \mid \lambda \in \Lambda(k)\}. \quad (7)$$

#### E. Fault Localization

As shown in Fig. 4(b), each EAE sequentially generates independent EAEO in conjunction with the STW process. In order to monitor fault occurrences and carry fault information

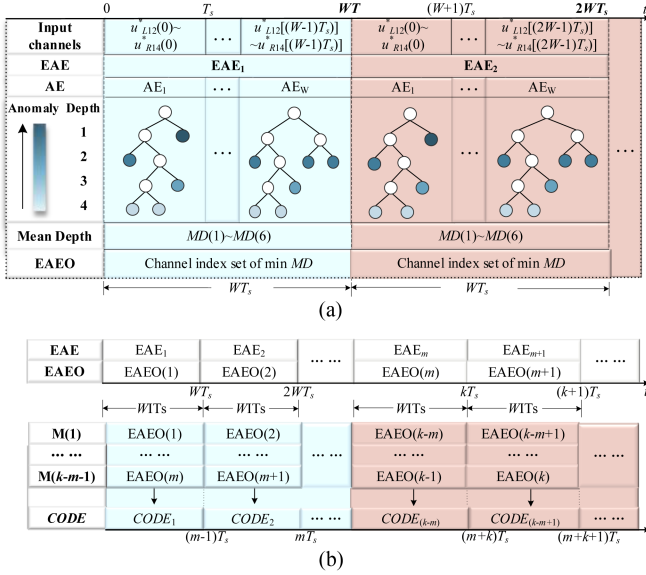


Fig. 4. EAE for MNER. (a) AEs and EAES. (b) Buffer  $M$  and  $CODE$ .

#### B. AE for MNER

As shown in Fig. 4(a), an AE is a nonlinear data structure, containing a number of levels. Each level is composed of the nodes, where each node is separated into two subnodes in the next level. Finally, each AE has six terminal nodes located at the layer terminals, which store the data of corresponding sampling channels and cannot be further divided.

Furthermore, the numerous AEs are established based on the input vector composed of six sampling channels representing the normalized mean interarm voltages (NMIVs):  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ , defined as

$$\begin{cases} U_{L1i}^* = \frac{2U_{L1i} - (U_j - U_1)}{|U_j - U_1|} = \frac{2U_{L1i}}{|U_j - U_1|} \pm 1 \\ U_{R1i}^* = \frac{2U_{R1i} - (U_j - U_1)}{|U_j - U_1|} = \frac{2U_{R1i}}{|U_j - U_1|} \pm 1 \end{cases} \quad (2)$$

To compute NMIVs, a STW of a fixed length  $W$  is employed, which continuously advances and segments the IVs, and converts them into short-term means MIVs. Afterward, MIVs are normalized into NMIVs to achieve dimensional unification among channels.

#### C. EAE for MNER

An EAE is composed of  $W$  neighboring AEs, including  $AE_1 \sim AE_w$ . Fig. 4(a) shows the EAES for the quad-port MNER. In each EAE, channel  $i$  ( $1 \leq i \leq 6$ ) in the  $j$ th AE corresponds with a depth  $D(i, j)$ , indicating its level position in the  $j$ th AE.

Fig. 4(a) also shows the anomalous degree for nodes in EAE with the different colors. Along with the darkening of color, the

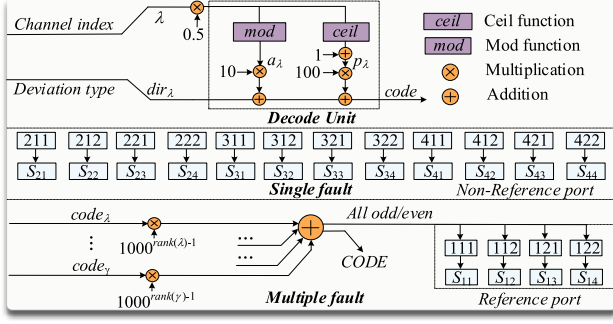


Fig. 5. Composite decoder for fault localization.

in the MNER, a buffer  $M$  is created to store  $m$  successive EAEOs, which is expressed as

$$\begin{cases} M = \{M(1), M(2), \dots, M(m-1), M(m)\} \\ M(1) = \text{EAEO}(k-m+1), \dots, M(m) = \text{EAEO}(k) \end{cases} \quad (8)$$

where  $M(1), \dots, M(m)$  represent  $m$  successive elements.

The buffer  $M$  is updated every  $WTs$ , with the oldest EAEO is removed and the newest EAEO is inserted. Upon inspection, if the  $m$  neighboring values in the buffer are consistently identical  $M(1) = M(2) = \dots = M(m) = \{\lambda, dir_\lambda\}$ , these abnormal channels with corresponding deviation types are detected.

Based on the buffering result, the composite decoder for fault localization is employed to generate the integer  $CODE$ , which maps the channel anomaly to switch physical location, as shown in Fig. 5.

1) *Fault Localization of Nonreference Port*: As shown in Fig. 5, after buffering the EAEOs and obtaining  $\lambda$  and  $dir_\lambda$ , function  $ceil$  and  $mod$  are employed to obtain the variables  $p_\lambda$  and  $a_\lambda$ . Specifically, function  $ceil$  and  $mod$ , respectively, generate the smallest integer greater than or equal to  $\lambda/2$ , and the residual of  $\lambda/2$ , expressed as

$$p_\lambda = \text{ceil}\left(\frac{\lambda}{2}\right) + 1, a_\lambda = \text{mod}\left(\frac{\lambda}{2}\right) \quad (9)$$

where the symbol  $p$  represents the port number ( $p = 1, 2, 3, 4$ ). Symbol  $a$  indicates the arm location ( $a = 1, 2$ ), with 1 referring to the left arm and 2 referring to the right arm.

Once the deviation type, port location, and arm location are determined,  $code$  is generated by incorporating the decimal-weighting coefficients. Subsequently,  $CODE$  is generated by aggregating these potential  $codes$ , which are expressed as

$$\begin{cases} code = 100p_\lambda + 10a_\lambda + dir_\lambda \\ CODE = \sum_{\lambda \in \Lambda} code_\lambda \times 1000^{r(\lambda)-1} \end{cases} \quad (10)$$

where  $r(\lambda)$  is the rank of  $\lambda$  within channels by ascending order.

Following  $CODE$  determination, the physical switch location is uniquely mapped, and a fault flag is triggered to localize the faulty switch.

2) *Fault Localization of Reference Port*: The faulty switch in reference port is localized through group anomaly detection, when all the odd-indexed  $U_{L12}^* \sim U_{L14}^*$  or even-indexed  $U_{R12}^* \sim U_{R14}^*$  channels are detected as anomalies, as given in Table III. In this case, the corresponding  $CODE$  is directly

TABLE III  
FAULT LOCALIZATION IN REFERENCE PORT

Abnormal group	Deviate direction	Faulty switch	CODE
$U_{L12}^* \sim U_{L14}^*$	↓	$S_{11}/S_{13}$	111/121
$U_{R12}^* \sim U_{R14}^*$	↑	$S_{12}/S_{14}$	112/122

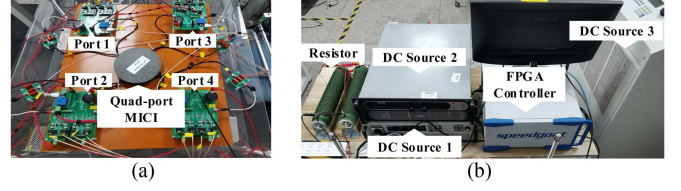


Fig. 6. Experimental prototype of the quad-port MNER. (a) Quad-port MNER. (b) FPGA controller, power supply, and resistive load.

TABLE IV  
EXPERIMENTAL SYSTEM PARAMETERS

Parameters	Details	Parameters	Details
Voltage: $U_1, U_2, U_4$ (V)	80, 60, 75	Winding turns: $W_1 \sim W_4$	3, 3, 3, 3
Switching period: $T$ ( $\mu s$ )	10	Capacitance: $C_1 \sim C_4$ ( $\mu F$ )	820
Resistance: $R_{LD}$ ( $\Omega$ )	60	Magnetic material	Ferrite
Buffer length: $m$	4 Points	Window length: $W$	10 Points

#### IV. EXPERIMENTAL VERIFICATION

To verify the proposed method, a quad-port MNER prototype was built, as shown in Fig. 6(a) and (b). In the prototype, port 1, 2, and 4 are connected to dc power supplies  $U_1, U_2$ , and  $U_4$  respectively, while port 3 is connected to a resistive load  $R_{LD}$ , and sixteen identical SiC MOSFETs are employed.

The prototype parameters of the quad-port MNER are determined in Table IV. Meanwhile, the proposed fault localization method is implemented in the Speedgoat FPGA controller. In order to simulate switch OCF, the drive signal of corresponding MOSFET is set to zero.

##### A. Case 1: Single-Switch OCF

In this case, OCF occurs to  $S_{23}$  in the nonreference port at 50.00 ms. As shown in Fig. 7(a) and (b), initially, IVs exhibit symmetry and NMIVs stabilize near 0, with  $CODE$  equal to 0. After the  $S_{23}$  OCF,  $u_{R12}$  waveform distorts, causing  $U_{R12}^*$  to deviate negatively. At 50.01 ms,  $CODE$  is triggered to 221, and faulty switch  $S_{23}$  is localized within one switching period.

In this case, OCF occurs to  $S_{12}$  in the reference port at 50.00 ms. As shown in Fig. 8(a) and (b), initially, IVs exhibit symmetry and NMIVs stabilize near 0, with  $CODE$  equal to 0. After fault, all even-indexed NMIVs  $U_{L12}^* \sim U_{L14}^*$  deviate positively. Finally, at 50.01 ms, group anomaly detection triggers  $CODE$  to 112, localizing faulty switch  $S_{12}$  within one switching period.

##### B. Case 2: Single-Switch OCF Under Input-Voltage Change

In this case, under the scenario of  $S_{23}$  OCF, the  $U_2$  step-change from 60 to 75 V occurs at 80.00 ms. As shown in Fig. 9(a) and (b), prior to this voltage disturbance, all NMIVs except the abnormal  $U_{R12}^*$  stabilize near 0, while  $U_{R12}^*$  stabilizes

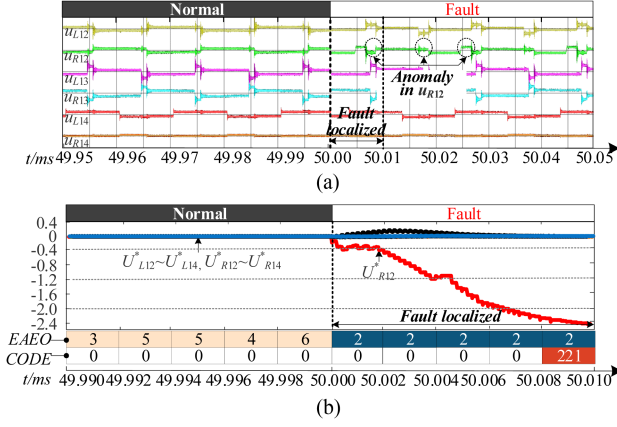


Fig. 7. Experimental waveforms under  $S_{23}$  OCF. (a) IVs including  $u_{L12} \sim u_{L14}$  (250 V/div),  $u_{R12} \sim u_{R14}$  (250 V/div), with a time base of 5  $\mu$ s/div. (b) NMIVs (including  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ ), EAEO, and CODE.

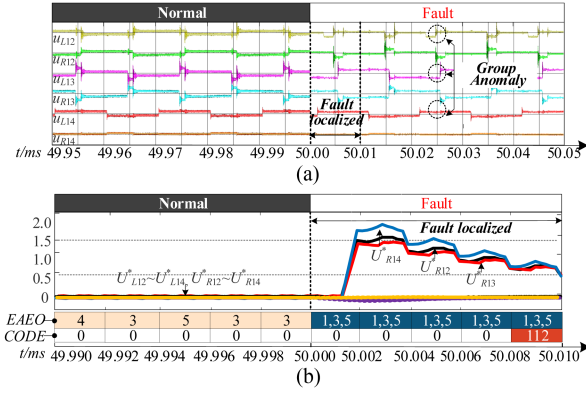


Fig. 8. Experimental waveforms under  $S_{12}$  OCF. (a) IVs including  $u_{L12} \sim u_{L14}$  (250 V/div),  $u_{R12} \sim u_{R14}$  (250 V/div), with a time base of 5  $\mu$ s/div. (b) NMIVs (including  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ ), EAEO, and CODE.

the waveform of  $u_{L12}$  and  $u_{L14}$ , which drives  $U_{L12}^*$  and  $U_{L14}^*$  to fluctuate gradually. Critically, EAEOs buffering successfully isolates these anomalies in  $U_{L12}^*$  and  $U_{L14}^*$  induced by voltage disturbance, and the CODE stabilizes at 221, ensuring reliable fault localization across input-voltage change.

### C. Case 3: Single-Switch OCF Under Load Change

In this case, under the scenario of  $S_{31}$  OCF, the step-change of  $R_{LD}$  from 60 to 80  $\Omega$  occurs at 80.00 ms. As shown in Fig. 10(a) and (b), prior to this load disturbance, all NMIVs except the abnormal  $U_{L13}^*$  stabilize near 0, while  $U_{L13}^*$  stabilizes near  $-1$ , with CODE at 311. At 80.00 ms, load disturbance triggers waveform distortion of  $u_{R13}$ , which drives  $U_{R13}^*$  to fluctuate. Critically, EAEOs buffering successfully isolates this anomaly in  $U_{R13}^*$  induced by load disturbance, and the CODE stabilizes at 311, ensuring reliable localization across load change.

### D. Case 4: Multiswitch OCF

In this case, concurrent multiswitch faults occur to  $S_{21}$  and  $S_{32}$  at 50.00 ms. As shown in Fig. 11(a) and (b), initially, IVs exhibit symmetry and NMIVs stabilize near 0, with CODE equal to 0.

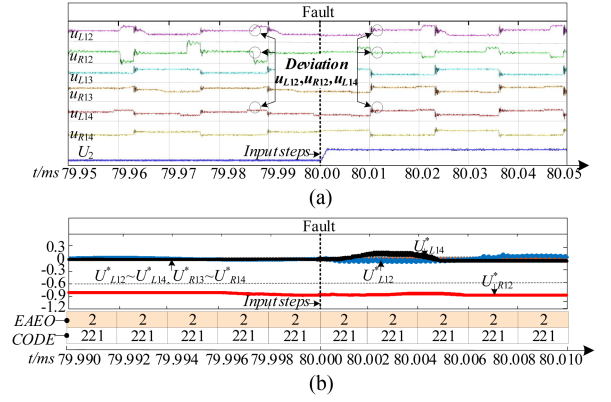


Fig. 9. Experimental waveforms under  $S_{23}$  OCF and input-voltage-change. (a) IVs including  $u_{L12} \sim u_{L14}$  (250 V/div) and  $u_{R12} \sim u_{R14}$  (250 V/div), and DC voltage  $U_2$  (100 V/div), with a time base of 5  $\mu$ s/div. (b) NMIVs (including  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ ), EAEO, and CODE.

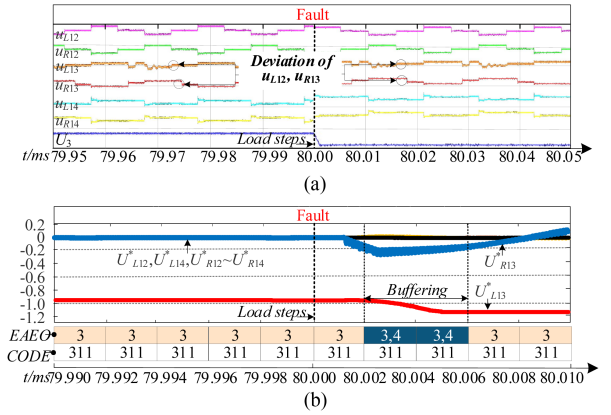


Fig. 10. Experimental waveforms under  $S_{31}$  OCF and load-change. (a) IVs including  $u_{L12} \sim u_{L14}$  (250 V/div) and  $u_{R12} \sim u_{R14}$  (250 V/div), and DC voltage  $U_3$  (100 V/div) with a time base of 5  $\mu$ s/div. (b) NMIVs (including  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ ), EAEO, and CODE.

Following the concurrent fault occurrence in  $S_{21}$  and  $S_{32}$ ,  $U_{L12}^*$  and  $U_{R13}^*$  exhibit positive and negative deviation, respectively. Finally, at 50.02 ms, group anomaly detection triggers CODE to 211312, achieving multifault localization of faulty switch  $S_{21}$  and  $S_{32}$  within two switching period.

### E. Comparison of Fault Localization Methods

Table V gives the comparison of the proposed method and typical existing methods [6], [9], [10], [12], [14] applied in quad-port MNER, evaluating seven key metrics: math models; threshold setting; extra hardware; localization time; multifaults localization; data volume; and computational burden.

In contrast with the existing methods, this proposed method achieves following significant benefits.

- 1) Extra hardware cost is reduced based on the innovative feature extraction of IVs.
- 2) Accurate localization is achieved within one switching period, by means of leveraging the sparsity-based fault candidate identification and direct statistical analysis, instead of mathematical modeling or threshold setting.

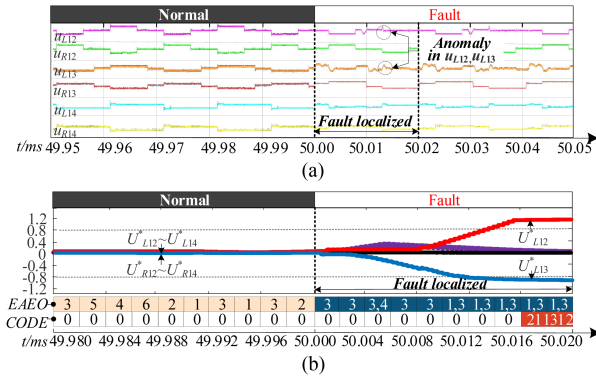


Fig. 11. Experimental waveforms under  $S_{21}$  and  $S_{32}$  OCF. (a) IVs including  $u_{L12} \sim u_{L14}$  (250 V/div) and  $u_{R12} \sim u_{R14}$  (250 V/div), with a time base of 5  $\mu$ s/div. (b) NMIVs (including  $U_{L12}^* \sim U_{L14}^*$ ,  $U_{R12}^* \sim U_{R14}^*$ ), EAEO, and CODE.

TABLE V  
COMPARISON OF FAULT LOCALIZATION METHODS

Method	Zhuo et al. [6]	Shi et al. [9]	Zheng et al. [10]	Yang et al. [12]	Xing et al. [14]	Proposed method
Math Models	Yes	Yes	No	No	No	No
Threshold Setting	Yes	Yes	Yes	Yes	Yes	No
Extra Hardware	8 sensors	8 sensors	4 sensors & 3 windings	8 sensors	8 sensors	6 sensors
Multi-Faults Localization	No	No	No	No	No	Yes
Data Volume	Large	Large	Medium	Medium	Large	Low
Computational Burden	Medium	High	Medium	High	High	Medium
Localization Time	3T	3T	2T	2T	2T	T

- 3) Computational burden and data volume are alleviated, through the employment of the lightweight-anomaly-encoder-based inference.
- 4) Concurrent multiswitch faults are effectively addressed, through scalable composite decoder.

## V. CONCLUSION

In this letter, a rapid and reliable data-driven adaptive switch OCF localization method is proposed for MNER. Numerous EAEs and decoders are constructed using adaptive datasets containing samples of IVs to localize faulty switch within MNER.

The proposed method not only reduces hardware cost by minimizing sensor requirements, but also eliminates the mathematical model and manual threshold setting. The experimental results verify the feasibility and effectiveness of the proposed method.

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